

Shenzhen Toby Technology Co., Ltd.



Report No.: TBR-C-202308-0123-8

Page: 1 of 60

EMC TEST REPORT

Certificate No. : TBC-C-202308-0123-2

Applicant : XonTel Technology Trd. Co. W.L.L

Equipment Under Test (EUT)

EUT Name : Audio Amplifier

Model No. : XT-160AMP

Series Model No. : ----

Brand Name : XonTel

Receipt Date : 2023-08-18

Test Date : 2023-08-18 to 2023-09-15

Issue Date : 2023-09-15

Standards : EN 55032:2015/A1:2020

EN IEC 61000-3-2:2019/A1:2021 EN 61000-3-3:2013/A2:2021 EN 55035:2017/A11:2020

Conclusions : PASS

In the configuration tested, the EUT complied with the standards specified above. The EUT technically complies with the Council Directive 2014/53/EU relating to radio equipment.

Test/Witness Engineer :

Engineer Supervisor : WW SV

Engineer Manager :

CE

This report details the results of the testing carried out on one sample. The results contained in this test report do not relate to other samples of the same product. The manufacturer should ensure that all products in series production are in conformity with the product sample detailed in the report.

TB-RF-075-1.0



TABLE OF CONTENTS

1	GENERAL INFORMATION	
	1.1 Client Information	
	1.2 General Description of EUT (Equipment Under Test)	
	1.3 Block Diagram Showing the Configuration of System Tested	
	1.4 Description of Support Units	
	1.5 Description of Operating Mode	
	1.6 Performance Criteria	
	1.7 Measurement Uncertainty	
	1.8 Test Facility	
2	TEST RESULTS SUMMARY	
3	TEST SOFTWARE	
4	TEST EQUIPMENT	
5	CONDUCTED DISTURBANCE TEST (AC PORT)	16
	5.1 Test Standard and Limit	
	5.2 Test Setup	16
	5.3 Test Procedure	
	5.4 Deviation From Test Standard	
	5.5 Test Data	
6	CONDUCTED EMISSIONS (WIRED NETWORK PORT)	
	6.1 Test Standard and Limit	18
	6.2 Test Setup	19
	6.3 Test Procedure	
	6.4 Deviation From Test Standard	
	6.5 Test Data	
7	CONDUCTED DIFFERENTIAL VOLTAGE EMISSIONS	
	7.1 Test Standard and Limit	
	7.2 Test Setup	
	7.3 Test Procedure	
	7.4 Deviation From Test Standard	
-	7.5 Test Data	
8	RADIATED EMISSION TEST	
	8.1 Test Standard and Limit	
	8.2 Test Setup	
	8.3 Test Procedure	
	8.5 Test Data	
9	HARMONIC CURRENT EMISSION TEST	
9	9.1 Test Standard and Limit	
	9.2 Test Standard and Limit	
	9.3 Test Procedure	
	9.4 Deviation From Test Standard	
	9.5 Test Data	
10	VOLTAGE FLUCTUATION AND FLICKER TEST	
. 5	10.1 Test Standard and Limit	
	10.2 Test Setup	
	10.3 Test Procedure	
	10.4 Deviation From Test Standard	
回忆的特征		





Report No.: TBR-C-202308-0123-8 Page: 3 of 60

11 ELECTROSTATIC DISCHARGE IMMUNITY TEST 28 11.1 Test Standard and Limit 28 11.2 Test Setup 28 11.3 Test Procedure 28 11.4 Deviation From Test Standard 25 11.5 Test Data 25 12 RADIATED ELECTROMAGNETIC FIELD IMMUNITY TEST 36 12.1 Test Standard and Limit 30 12.2 Test Setup 30 12.3 Test Procedure 31 12.5 Test Data 31 13 ELECTRICAL FAST TRANSIENT/BURST TEST 32 13.1 Test Standard and Limit 32 13.2 Test Setup 32 13.3 Test Procedure 32 13.4 Deviation From Test Standard 32 12.5 Test Data 32 14 SURGE IMMUNITY TEST 33 14.1 Test Standard and Limit 33 14.2 Test Setup 33 14.3 Test Procedure 33 14.5 Test Data 33 15.7 Test Standard and Limit 33 15.8 Test Data 34 15.9 Test Sterup 34 15.1 Test Standard and Limit 34 15.2 Test Setup
11.1 Test Standard and Limit 28 11.2 Test Setup. 28 11.3 Test Procedure. 25 11.4 Deviation From Test Standard. 25 11.5 Test Data. 25 12 RADIATED ELECTROMAGNETIC FIELD IMMUNITY TEST. 36 12.1 Test Standard and Limit 36 12.2 Test Setup. 30 12.3 Test Procedure. 31 12.4 Deviation From Test Standard. 31 12.5 Test Data. 31 13 ELECTRICAL FAST TRANSIENT/BURST TEST. 32 13.1 Test Standard and Limit 33 13.2 Test Setup. 32 13.3 Test Procedure. 32 13.4 Deviation From Test Standard. 33 14.5 Test Data. 33 14.1 Test Standard and Limit 33 14.2 Test Stetup. 33 14.3 Test Procedure. 33 14.4 Deviation From Test Standard. 33 14.5 Test Data. 33 15.1 Test Standard and Limit 34 15.2 Test Standard and Limit 34 15.3 Test Procedure. 34 15.4 Deviation From Test Standard. 35 <
11.2 Test Setup. 25 11.3 Test Procedure. 25 11.4 Deviation From Test Standard 25 11.5 Test Data. 25 11.5 Test Data. 25 12 RADIATED ELECTROMAGNETIC FIELD IMMUNITY TEST. 36 12.1 Test Standard and Limit 30 12.2 Test Setup. 30 12.3 Test Procedure. 31 12.5 Test Data. 31 13 ELECTRICAL FAST TRANSIENT/BURST TEST. 32 13.1 Test Standard and Limit 32 13.2 Test Setup. 32 13.3 Test Procedure. 32 13.4 Deviation From Test Standard 33 14.5 Test Data. 32 14.5 Test Standard and Limit 33 14.1 Test Standard and Limit 33 14.2 Test Setup. 33 14.3 Test Procedure. 33 14.4 Deviation From Test Standard 33 14.5 Test Data. 33 15.7 Test Standard and Limit 34 15.2 Test Setup. 34 15.3 Test Procedure. 34 15.4 Deviation From Test Standard. 35 15.5 Test Data.
11.4 Deviation From Test Standard 25 11.5 Test Data 25 12 RADIATED ELECTROMAGNETIC FIELD IMMUNITY TEST 36 12.1 Test Standard and Limit 36 12.2 Test Setup 30 12.3 Test Procedure 31 12.4 Deviation From Test Standard 31 12.5 Test Data 31 13 ELECTRICAL FAST TRANSIENT/BURST TEST 32 13.1 Test Standard and Limit 32 13.2 Test Setup 32 13.3 Test Procedure 32 13.4 Deviation From Test Standard 32 12.5 Test Data 33 14.1 Test Standard and Limit 33 14.2 Test Setup 33 14.3 Test Procedure 33 14.4 Deviation From Test Standard 33 14.5 Test Data 33 15 RF COMMON MODE 34 15.1 Test Standard and Limit 34 15.2 Test Setup 34 15.3 Test Procedure 34 15.5 Test Data 35 16.1 Test Standard and Limit 36 16.2 Test Standard and Limit 36 16.2 Test Standard and Limit
11.5 Test Data. 25 12 RADIATED ELECTROMAGNETIC FIELD IMMUNITY TEST 36 12.1 Test Standard and Limit 36 12.2 Test Setup. 36 12.3 Test Procedure 31 12.4 Deviation From Test Standard 31 12.5 Test Data. 31 13 ELECTRICAL FAST TRANSIENT/BURST TEST 32 13.1 Test Standard and Limit 35 13.2 Test Setup. 32 13.3 Test Procedure 32 13.4 Deviation From Test Standard 32 12.5 Test Data 33 14.1 Test Standard and Limit 33 14.2 Test Setup. 33 14.3 Test Procedure 33 14.4 Deviation From Test Standard 33 14.5 Test Data 33 15 RF COMMON MODE 34 15.1 Test Standard and Limit 34 15.2 Test Setup. 34 15.3 Test Procedure 34 15.4 Deviation From Test Standard 35 15.5 Test Data 35 16.1 Test Standard and Limit 36 16.2 Test Steup 36 16.3 Test Procedure
12 RADIATED ELECTROMAGNETIC FIELD IMMUNITY TEST. 36 12.1 Test Standard and Limit 36 12.2 Test Setup. 31 12.4 Deviation From Test Standard. 31 12.5 Test Data. 31 13 ELECTRICAL FAST TRANSIENT/BURST TEST. 32 13.1 Test Standard and Limit 35 13.2 Test Setup. 32 13.3 Test Procedure. 32 13.4 Deviation From Test Standard. 32 12.5 Test Data. 32 14.1 Test Standard and Limit 33 14.2 Test Setup. 33 14.3 Test Procedure. 33 14.4 Deviation From Test Standard. 33 14.5 Test Data. 33 15. Test Data. 33 15.1 Test Standard and Limit 34 15.2 Test Data. 34 15.3 Test Procedure. 34 15.5 Test Data. 35 15.6 Test Data. 35 16.7 Test Standard and Limit 36 16.7 Test Standard and Limit 36 16.7 Test Standard and Limit 36 16.5 Test Data. 36
12.1 Test Standard and Limit 36 12.2 Test Setup. 36 12.3 Test Procedure. 31 12.4 Deviation From Test Standard 31 12.5 Test Data 31 13 ELECTRICAL FAST TRANSIENT/BURST TEST. 32 13.1 Test Standard and Limit 32 13.2 Test Setup. 32 13.3 Test Procedure. 32 13.4 Deviation From Test Standard. 32 12.5 Test Data 32 14. SURGE IMMUNITY TEST 33 14.1 Test Standard and Limit 33 14.2 Test Setup. 33 14.3 Test Procedure. 33 14.4 Deviation From Test Standard 33 14.5 Test Data 33 15.1 Test Standard and Limit 34 15.2 Test Data 34 15.3 Test Procedure. 34 15.4 Deviation From Test Standard. 35 15.5 Test Data 35 16.1 Test Standard and Limit 36 16.2 Test Setup. 36 16.3 Test Procedure. 36 16.4 Deviation From Test Standard. 36 16.5 Test Data 36
12.2 Test Setup
12.3 Test Procedure. 31 12.4 Deviation From Test Standard. 31 12.5 Test Data. 31 13 ELECTRICAL FAST TRANSIENT/BURST TEST. 32 13.1 Test Standard and Limit 32 13.2 Test Setup. 32 13.3 Test Procedure. 32 13.4 Deviation From Test Standard. 32 12.5 Test Data. 32 14 SURGE IMMUNITY TEST. 33 14.1 Test Standard and Limit 33 14.2 Test Setup. 33 14.3 Test Procedure. 33 14.4 Deviation From Test Standard. 33 14.5 Test Data. 33 15 RF COMMON MODE. 34 15.1 Test Standard and Limit 34 15.2 Test Setup. 34 15.3 Test Procedure. 34 15.4 Deviation From Test Standard. 35 15.5 Test Data. 35 16 POWER FREQUENCY MAGNETIC FIELD IMMUNITY TEST. 36 16.1 Test Standard and Limit 36 16.2 Test Setup. 36 16.3 Test Procedure. 36 16.4 Deviation From Test Standard. 36 16
12.4 Deviation From Test Standard 31 12.5 Test Data 31 13 ELECTRICAL FAST TRANSIENT/BURST TEST 32 13.1 Test Standard and Limit 32 13.2 Test Setup 32 13.3 Test Procedure 32 13.4 Deviation From Test Standard 32 12.5 Test Data 32 14 SURGE IMMUNITY TEST 33 14.1 Test Standard and Limit 33 14.2 Test Setup 33 14.3 Test Procedure 33 14.4 Deviation From Test Standard 33 14.5 Test Data 33 15.1 Test Standard and Limit 34 15.2 Test Setup 34 15.3 Test Procedure 34 15.4 Deviation From Test Standard 35 15.5 Test Data 35 16 POWER FREQUENCY MAGNETIC FIELD IMMUNITY TEST 36 16.1 Test Standard and Limit 36 16.2 Test Setup 36 16.5 Test Data 36 16.5 Test Data 36 16.5 Test Data 36 16.5 Test Data 37 17.1 Test Standard and Limit 36
12.5 Test Data. 31 13 ELECTRICAL FAST TRANSIENT/BURST TEST. 32 13.1 Test Standard and Limit 32 13.2 Test Setup. 32 13.3 Test Procedure. 32 13.4 Deviation From Test Standard. 32 12.5 Test Data. 32 14 SURGE IMMUNITY TEST. 33 14.1 Test Standard and Limit 33 14.2 Test Setup. 33 14.3 Test Procedure. 33 14.4 Deviation From Test Standard. 33 14.5 Test Data. 33 15.1 Test Standard and Limit 34 15.2 Test Setup. 34 15.3 Test Procedure. 34 15.4 Deviation From Test Standard. 35 15.5 Test Data. 35 16 POWER FREQUENCY MAGNETIC FIELD IMMUNITY TEST. 36 16.1 Test Standard and Limit 36 16.2 Test Setup. 36 16.3 Test Procedure. 36 16.4 Deviation From Test Standard. 36 16.5 Test Data. 36 16.5 Test Data. 36 17 VOLTAGE DIPS AND INTERRUPTIONS IMMUNITY TEST. 37
13 ELECTRICAL FAST TRANSIENT/BURST TEST 32 13.1 Test Standard and Limit 32 13.2 Test Setup 32 13.3 Test Procedure 32 13.4 Deviation From Test Standard 32 12.5 Test Data 32 14 SURGE IMMUNITY TEST 33 14.1 Test Standard and Limit 33 14.2 Test Setup 33 14.3 Test Procedure 33 14.4 Deviation From Test Standard 33 15.1 Test Standard and Limit 34 15.2 Test Setup 34 15.3 Test Procedure 34 15.4 Deviation From Test Standard 35 15.5 Test Data 35 16 POWER FREQUENCY MAGNETIC FIELD IMMUNITY TEST 36 16.1 Test Standard and Limit 36 16.2 Test Setup 36 16.3 Test Procedure 36 16.4 Deviation From Test Standard 36 16.5 Test Data 36 17 VOLTAGE DIPS AND INTERRUPTIONS IMMUNITY TEST 37 17.1 Test Standard and Limit 36
13.1 Test Standard and Limit 32 13.2 Test Setup 32 13.3 Test Procedure 32 13.4 Deviation From Test Standard 32 12.5 Test Data 32 14 SURGE IMMUNITY TEST 33 14.1 Test Standard and Limit 33 14.2 Test Setup 33 14.3 Test Procedure 33 14.4 Deviation From Test Standard 33 14.5 Test Data 33 15.1 Test Standard and Limit 34 15.2 Test Setup 34 15.3 Test Procedure 34 15.5 Test Data 35 16 POWER FREQUENCY MAGNETIC FIELD IMMUNITY TEST 36 16.1 Test Standard and Limit 36 16.2 Test Setup 36 16.3 Test Procedure 36 16.4 Deviation From Test Standard 36 16.5 Test Data 36 17 VOLTAGE DIPS AND INTERRUPTIONS IMMUNITY TEST 37 17.1 Test Standard and Limit 37
13.2 Test Setup
13.3 Test Procedure 32 13.4 Deviation From Test Standard 32 12.5 Test Data 32 14 SURGE IMMUNITY TEST 33 14.1 Test Standard and Limit 33 14.2 Test Setup 33 14.3 Test Procedure 33 14.4 Deviation From Test Standard 33 14.5 Test Data 33 15.1 Test Standard and Limit 34 15.2 Test Setup 34 15.3 Test Procedure 34 15.4 Deviation From Test Standard 35 15.5 Test Data 35 16 POWER FREQUENCY MAGNETIC FIELD IMMUNITY TEST 36 16.1 Test Standard and Limit 36 16.2 Test Setup 36 16.3 Test Procedure 36 16.4 Deviation From Test Standard 36 16.5 Test Data 36 17 VOLTAGE DIPS AND INTERRUPTIONS IMMUNITY TEST 37 17.1 Test Standard and Limit 37 17.1 Test Standard and Limit 36
13.4 Deviation From Test Standard 32 12.5 Test Data 32 14 SURGE IMMUNITY TEST 33 14.1 Test Standard and Limit 33 14.2 Test Setup 33 14.3 Test Procedure 33 14.4 Deviation From Test Standard 33 14.5 Test Data 33 15 RF COMMON MODE 34 15.1 Test Standard and Limit 34 15.2 Test Setup 34 15.3 Test Procedure 34 15.4 Deviation From Test Standard 35 15 Fest Data 35 16 POWER FREQUENCY MAGNETIC FIELD IMMUNITY TEST 36 16.1 Test Standard and Limit 36 16.2 Test Setup 36 16.3 Test Procedure 36 16.4 Deviation From Test Standard 36 16.5 Test Data 36 17 VOLTAGE DIPS AND INTERRUPTIONS IMMUNITY TEST 37 17.1 Test Standard and Limit 37
12.5 Test Data. 32 14 SURGE IMMUNITY TEST. 33 14.1 Test Standard and Limit 33 14.2 Test Setup. 33 14.3 Test Procedure. 33 14.4 Deviation From Test Standard 33 14.5 Test Data. 33 15 RF COMMON MODE. 34 15.1 Test Standard and Limit 34 15.2 Test Setup. 34 15.3 Test Procedure. 34 15.4 Deviation From Test Standard 35 15 Fost Data. 35 16 POWER FREQUENCY MAGNETIC FIELD IMMUNITY TEST 36 16.1 Test Standard and Limit 36 16.2 Test Setup. 36 16.3 Test Procedure. 36 16.4 Deviation From Test Standard 36 16.5 Test Data. 36 17 VOLTAGE DIPS AND INTERRUPTIONS IMMUNITY TEST 37 17.1 Test Standard and Limit 37
14 SURGE IMMUNITY TEST 33 14.1 Test Standard and Limit 33 14.2 Test Setup 33 14.3 Test Procedure 33 14.4 Deviation From Test Standard 33 14.5 Test Data 33 15 RF COMMON MODE 34 15.1 Test Standard and Limit 34 15.2 Test Setup 34 15.3 Test Procedure 34 15.4 Deviation From Test Standard 35 15 POWER FREQUENCY MAGNETIC FIELD IMMUNITY TEST 36 16.1 Test Standard and Limit 36 16.2 Test Setup 36 16.3 Test Procedure 36 16.4 Deviation From Test Standard 36 16.5 Test Data 36 17 VOLTAGE DIPS AND INTERRUPTIONS IMMUNITY TEST 37 17.1 Test Standard and Limit 37
14.1 Test Standard and Limit 33 14.2 Test Setup 33 14.3 Test Procedure 33 14.4 Deviation From Test Standard 33 14.5 Test Data 33 15 RF COMMON MODE 34 15.1 Test Standard and Limit 34 15.2 Test Setup 34 15.3 Test Procedure 34 15.4 Deviation From Test Standard 35 15.5 Test Data 35 16 POWER FREQUENCY MAGNETIC FIELD IMMUNITY TEST 36 16.1 Test Standard and Limit 36 16.2 Test Setup 36 16.3 Test Procedure 36 16.4 Deviation From Test Standard 36 16.5 Test Data 36 17 VOLTAGE DIPS AND INTERRUPTIONS IMMUNITY TEST 37 17.1 Test Standard and Limit 37
14.2 Test Setup
14.3 Test Procedure 33 14.4 Deviation From Test Standard 33 14.5 Test Data 33 15 RF COMMON MODE 34 15.1 Test Standard and Limit 34 15.2 Test Setup 34 15.3 Test Procedure 34 15.4 Deviation From Test Standard 35 15.5 Test Data 35 16 POWER FREQUENCY MAGNETIC FIELD IMMUNITY TEST 36 16.1 Test Standard and Limit 36 16.2 Test Setup 36 16.3 Test Procedure 36 16.4 Deviation From Test Standard 36 16.5 Test Data 36 17 VOLTAGE DIPS AND INTERRUPTIONS IMMUNITY TEST 37 17.1 Test Standard and Limit 37 17.1 Test Standard and Limit 37
14.4 Deviation From Test Standard. 33 14.5 Test Data. 33 15 RF COMMON MODE. 34 15.1 Test Standard and Limit 34 15.2 Test Setup. 34 15.3 Test Procedure. 34 15.4 Deviation From Test Standard. 35 15.5 Test Data. 35 16 POWER FREQUENCY MAGNETIC FIELD IMMUNITY TEST. 36 16.1 Test Standard and Limit 36 16.2 Test Setup. 36 16.3 Test Procedure. 36 16.4 Deviation From Test Standard. 36 16.5 Test Data. 36 17 VOLTAGE DIPS AND INTERRUPTIONS IMMUNITY TEST. 37 17.1 Test Standard and Limit 37
14.5 Test Data 33 15 RF COMMON MODE 34 15.1 Test Standard and Limit 34 15.2 Test Setup 34 15.3 Test Procedure 34 15.4 Deviation From Test Standard 35 15.5 Test Data 35 16 POWER FREQUENCY MAGNETIC FIELD IMMUNITY TEST 36 16.1 Test Standard and Limit 36 16.2 Test Setup 36 16.3 Test Procedure 36 16.4 Deviation From Test Standard 36 16.5 Test Data 36 17 VOLTAGE DIPS AND INTERRUPTIONS IMMUNITY TEST 37 17.1 Test Standard and Limit 37
15 RF COMMON MODE
15.1 Test Standard and Limit 34 15.2 Test Setup 34 15.3 Test Procedure 34 15.4 Deviation From Test Standard 35 15.5 Test Data 35 16 POWER FREQUENCY MAGNETIC FIELD IMMUNITY TEST 36 16.1 Test Standard and Limit 36 16.2 Test Setup 36 16.3 Test Procedure 36 16.4 Deviation From Test Standard 36 16.5 Test Data 36 17 VOLTAGE DIPS AND INTERRUPTIONS IMMUNITY TEST 37 17.1 Test Standard and Limit 37
15.2 Test Setup
15.3 Test Procedure
15.4 Deviation From Test Standard
15.5 Test Data
16 POWER FREQUENCY MAGNETIC FIELD IMMUNITY TEST
16.1 Test Standard and Limit 36 16.2 Test Setup 36 16.3 Test Procedure 36 16.4 Deviation From Test Standard 36 16.5 Test Data 36 17 VOLTAGE DIPS AND INTERRUPTIONS IMMUNITY TEST 37 17.1 Test Standard and Limit 37
16.2 Test Setup
16.3 Test Procedure
16.4 Deviation From Test Standard
16.5 Test Data
17 VOLTAGE DIPS AND INTERRUPTIONS IMMUNITY TEST
17.1 Test Standard and Limit37
17.2 Test Setup
17.3 Test Procedure37
17.4 Deviation From Test Standard37
17.5 Test Data37
18 PHOTOGRAPHS - CONSTRUCTIONAL DETAILS38
19 PHOTOGRAPHS - TEST SETUP43
ATTACHMENT ACONDUCTED EMISSION DATA (AC MAINS)47
ATTACHMENT BRADIATED EMISSION TEST DATA
ATTACHMENT CVOLTAGE FLUCTUATION AND FLICKER TEST DATA
ATTACHMENT DELECTROSTATIC DISCHARGE TEST DATA54





Report No.: TBR-C-202308-0123-8 Page: 4 of 60

ATTACHMENT ERF FIELD STRENGTH SUSCEPTIBILITY TEST DATA	56
ATTACHMENT FELECTRICAL FAST TRANSIENT/BURST TEST DATA	57
ATTACHMENT GSURGE IMMUNITY TEST DATA	58
ATTACHMENT HCONDUCTED IMMUNITY TEST DATA	59
ATTACHMENT IVOLTAGE DIPS AND INTERRUPTIONS TEST DATA	60





Report No.: TBR-C-202308-0123-8 Page: 5 of 60

Revision History

Report No.	Version	Description	Issued Date
TBR-C-202308-0123-8	Rev.01	Initial issue of report	2023-09-15
	3	CHARLES THE STATE OF THE STATE	m Bi
4000	a Music		000
U.S. COL			
	MODE		
6033			
	000		
(103)	a Tube		0.03
	939		133
	THURS.		MOUNT





Page: 6 of 60

1 General Information

1.1 Client Information

Applicant : XonTel Technology Trd. Co. W.L.L		XonTel Technology Trd. Co. W.L.L
Address : Office 21, Justice Tower, Ali Al Salem St. Qibla, Kuwait City, State Kuwait. Zip code: 13065		Office 21, Justice Tower, Ali Al Salem St. Qibla, Kuwait City, State of Kuwait. Zip code: 13065
Manufacturer : XonTel Technology Trd. Co. W.L.L		XonTel Technology Trd. Co. W.L.L
Address : Office 21, Justice Tower, Ali Al Salem St. Qibla, Kuwait City, Sta Kuwait. Zip code: 13065		Office 21, Justice Tower, Ali Al Salem St. Qibla, Kuwait City, State of Kuwait. Zip code: 13065

1.2 General Description of EUT (Equipment Under Test)

EUT Name		Audio Amplifier
Model(s)	. 10	XT-160AMP
Model Difference	:	
Class of EUT	:	☐ Class A ☐ Class B
EUT Type	:	
Fx		2.4GHz
Power Supply		Input: AC 115V-230V
Software Version		V33
Hardware Version		V 1.0
Remark	:	The adapter provided by the applicant.

Remark:

Fx: Highest fundamental frequency generated or used within the EUT or highest frequency at which it operates.

Class A Equipment: the Equipment is not intended primarily for use in a residential environment

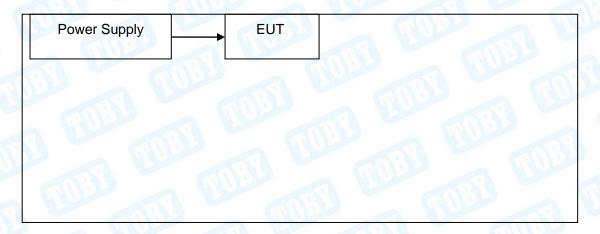
Class B Equipment: the Equipment is intended primarily for use in a residential environment.





Page: 7 of 60

1.3 Block Diagram Showing the Configuration of System Tested



1.4 Description of Support Units

	Equipment Information					
Name	Model	S/N	Manufacturer	Used "√"		
	A) (III)		-1			
	Cable Information					
Number	Shielded Type	Ferrite Core	Length	Note		





Page: 8 of 60

1.5 Description of Operating Mode

To investigate the maximum EMI emission characteristics generated from EUT, the test system was pre-scanning tested based on the consideration of following EUT operation mode or test configuration mode which possible have effect on EMI emission level. Each of these EUT operation mode(s) or test configuration mode(s) mentioned above was evaluated respectively.

Pretest Mode	Description
Mode 1	Power supply + Working Mode

The EUT system operated these modes were found to be the worst case during the pre-scanning test as Following:

For EMI Test			
Final Test Mode	Description		
Mode 1	Power supply + Working Mode		
For EMS Test			
Final Test Mode	Description		
Mode 1	Power supply + Working Mode		





Page: 9 of 60

1.6 Performance Criteria

General

General performance criteria are defined in 8.2, 8.3 and 8.4. These criteria shall be used during the testing of primary functions where no relevant annex is applicable.

When assessing the impact of a disturbance on a function, the assessment should take into consideration the function's performance prior to the application of the disturbance and only identify as failures those changes in performance that are a result of the disturbance.

Performance criterion A

The equipment shall continue to operate as intended without operator intervention. No degradation of performance, loss of function or change of operating state is allowed below a performance level specified by the manufacturer when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance. If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.

Performance criterion B

During the application of the disturbance, degradation of performance is allowed. However, no unintended change of actual operating state or stored data is allowed to persist after the test.

After the test, the equipment shall continue to operate as intended without operator intervention; no degradation of performance or loss of function is allowed, below a performance level specified by the manufacturer, when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance.

If the minimum performance level (or the permissible performance loss), or recovery time, is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.

Performance criterion C

Loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions. A reboot or re-start operation is allowed.

Information stored in non-volatile memory, or protected by a battery backup, shall not be lost.





Page: 10 of 60

1.7 Measurement Uncertainty

The reported uncertainty of measurement $y \pm U$, where expended uncertainty U is based on a standard uncertainty multiplied by a coverage factor of k=2, providing a level of

confidence of approximately 95 %.

Test Item	Expanded Uncertainty (U _{Lab})
Conducted Emission	±3.50 dB
Radiated Emission (9kHz to 30 MHz)	±4.60 dB
Radiated Emission (30MHz to 1000 MHz)	±4.60 dB
Radiated Emission (Above 1000MHz)	±4.50 dB
Temperature	±0.6℃
Humidity	±4%

1.8 Test Facility

The testing report were performed by the Shenzhen Toby Technology Co., Ltd., in their facilities located at 1/F., Building 6, Rundongsheng Industrial Zone, Longzhu, Xixiang, Bao'an District, Shenzhen, Guangdong, China. At the time of testing, the following bodies accredited the Laboratory:

CNAS (L5813)

The Laboratory has been accredited by CNAS to ISO/IEC 17025: 2017 General Requirements for the Competence of Testing and Calibration Laboratories for the competence in the field of testing. And the Registration No.: CNAS L5813.

A2LA Certificate No.: 4750.01

The laboratory has been accredited by American Association for Laboratory Accreditation(A2LA) to ISO/IEC 17025: 2017 General Requirements for the Competence of Testing and Calibration Laboratories for the technical competence in the field of Electrical Testing. And the A2LA Certificate No.: 4750.01.FCC Accredited Test Site Number: 854351.Designation Number: CN1223.

IC Registration No.: (11950A)

The Laboratory has been registered by Certification and Engineering Bureau of Industry Canada for radio equipment testing. The site registration: Site# 11950A. CAB identifier: CN0056.





Page: 11 of 60

2 Test Results Summary

	EMISSION ⊠ EN 55032:2015/A1:2020)		
Description of test items	Standards	Class	Results
Conducted disturbance at mains terminals	EN 55032:2015/A1:2020	Class A	Pass ₍₁₎
Conducted disturbance for asymmetric mode	EN 55032:2015/A1:2020	☐ Class B	N/A
Conducted differential voltage emission	EN 55032:2015/A1:2020	✓ Class BClass B	N/A ₍₂₎
Radiated Disturbance	EN 55032:2015/A1:2020	☐ Class A ☐ Class B	Pass
Harmonic current emissions	EN IEC 61000-3-2:2019/A1:2021	☐ Class A☐ Class D☐	N/A ₍₅₎
Voltage fluctuation and flicker	EN 61000-3-3:2013/A2:2021	NU	Pass

Note:

- (1) Class A/Class B: Applicable to AC mains power ports
- (2) Class A: Applicable to wired network ports, optical fibre ports with metallic shield or tension members and antenna ports.
 - Class B: Applicable to wired network ports, optical fibre ports with metallic shield or tension members, broadcast receiver tuner ports and antenna ports.
 - Applicable to ports listed above and intended to connect to cables longer than 3 m.
- (3) Class B: Applicable to TV broadcast receiver tuner ports with an accessible connector, RF modulator output ports and FM broadcast receiver tuner ports with an accessible connector.
- (4) Class A: Balanced three-phase equipment, Household appliances excluding equipment as Class D, Tools excluding portable tools, Dimmers for incandescent lamps, audio equipment, equipment not specified in one of the three other classes.
 - Class D: Equipment having a specified power less than or equal to 600 W of the following types: Personal computers and personal computer monitors and television receivers.
- (5) The power consumption of EUT is less than 75W and no Limits apply.





Report No.: TBR-C-202308-0123-8 Page: 12 of 60

Description of test items	Standards	Results
Electrostatic Discharge (ESD)	EN 61000-4-2: 2009	Pass
Continuous RF Electromagnetic Field Disturbances	EN IEC 61000-4-3:2020	Pass
EFT/B Immunity	EN 61000-4-4: 2012	Pass
Surge Immunity	EN 61000-4-5:2014/A1:2017	Pass
Continuous RF Disturbances	EN 61000-4-6: 2014	Pass
Power frequency magnetic field	EN 61000-4-8: 2010	N/A
Voltage dips	EN IEO 04000 4 44:0000	D.
Voltage interruptions	EN IEC 61000-4-11:2020	Pass





Report No.: TBR-C-202308-0123-8 Page: 13 of 60

3 Test Software

Test Item	Test Item Test Software		Version No.
Conducted Emission	EZ-EMC	EZ	CDI-03A2
Radiation Emission	EZ-EMC	EZ	FA-03A2RE
Radiation Emission	EZ-EMC	EZ	FA-03A2RE+
Radiation Immunity	TS+(J32-RS)	Tonsced	3.0.0.5
Harmonic Current	CTS4	CI	4.24.0
Voltage Fluctuation and Flicker	CTS4	CI	4.24.0
Conducted Immunity	IEC/EN 61000-6-4 Application	FRANKONIA	1.1.1
Electrical Fast Transient	lec.control	Nemtest	5.1.1.0
Surge	lec.control	Nemtest	5.1.1.0
Voltage Dip and Interruption	lec.control	Nemtest	5.1.1.0





Report No.: TBR-C-202308-0123-8 Page: 14 of 60

4 Test Equipment

	1	l	I	T	Ta.a
Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Due Date
EMI Test Receiver	Rohde & Schwarz	ESCI	100321	Jun. 20, 2023	Jun. 19, 2024
RF Switching Unit	Compliance Direction Systems Inc	RSU-A4	34403	Jun. 20, 2023	Jun. 19, 2024
AMN	SCHWARZBECK	NNBL 8226-2	8226-2/164	Jun. 20, 2023	Jun. 19, 2024
LISN	Rohde & Schwarz	ENV216	101131	Jun. 20, 2023	Jun. 19, 2024
Radiation Emiss	ion Test (A Site)			
Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Due Date
Spectrum Analyzer	Rohde & Schwarz	FSV40-N	102197	Jun. 20, 2023	Jun. 19, 2024
EMI Test Receiver	Rohde & Schwarz	ESPI	100010/007	Jun. 20, 2023	Jun. 19, 2024
Bilog Antenna	ETS-LINDGREN	3142E	00117537	Feb. 27, 2022	Feb.26, 2024
Horn Antenna	ETS-LINDGREN	3117	00143207	Feb. 26, 2022	Feb.25, 2024
Horn Antenna	SCHWARZBECK	BBHA 9170	1118	Feb. 26, 2022	Feb.25, 2024
Loop Antenna	SCHWARZBECK	FMZB 1519 B	1519B-059	Jun. 26, 2022	Jun.25, 2024
Pre-amplifier	SONOMA	310N	185903	Feb. 23, 2023	Feb.22, 2024
Pre-amplifier	HP	8449B	3008A00849	Feb. 23, 2023	Feb.22, 2024
HF Amplifier	Tonscend	TAP0184050	AP21C806129	Aug. 30, 2023	Aug. 29, 2024
Radiation Emiss	ion Test (B Site	e)		-	
Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Due Date
Spectrum Analyzer	Agilent	N9020A	MY49100060	Aug. 30, 2023	Aug. 29, 2024
Spectrum Analyzer	Rohde & Schwarz	FSV40-N	102197	Jun. 20, 2023	Jun. 19, 2024
EMI Test Receiver	Rohde & Schwarz	ESU-8	100472/008	Feb. 23, 2023	Feb.22, 2024
Bilog Antenna	SCHWARZBECK	VULB 9168	1225	Dec. 05, 2021	Dec. 04, 2023
Horn Antenna	SCHWARZBECK	BBHA 9120 D	2463	Feb. 26, 2022	Feb.25, 2024
Horn Antenna	SCHWARZBECK	BBHA 9170	1118	Jun. 26, 2022	Jun.25, 2024
Loop Antenna	SCHWARZBECK	FMZB 1519 B	1519B-059	Jun. 26, 2022	Jun.25, 2024
HF Amplifier	Tonscend	TAP9E6343	AP21C806117	Aug. 30, 2023	Aug. 29, 2024
HF Amplifier	Tonscend	TAP051845	AP21C806141	Aug. 30, 2023	Aug. 29, 2024
HF Amplifier	Tonscend	TAP0184050	AP21C806129	Aug. 30, 2023	Aug. 29, 2024
Harmonic Curre	nt and Voltage	Fluctuation ar	nd Flicker Test		
Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Due Date
Harmonic Flicker Test System	CI	5001ix-CTS-400	100321	Jun. 20, 2023	Jun. 19, 2024
AC Power Source	CI	500liX	59468	Jun. 20, 2023	Jun. 19, 2024
Discharge Immu	nity Test				
Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Due Date
ESD Tester	TESEQ	NSG437	304	Jun. 21, 2023	Jun. 20, 2024
Radiated Immun	ity Test				
Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Due Date





Report No.: TBR-C-202308-0123-8 Page: 15 of 60

Gestockte	and the	600			VIV.
LogPerBreitband- antenna Stacked LogPerBroadban d	SCHWARZBEC K	STLP 9129	162	N/A	N/A
Electric field probe	Narda	EP 601	811ZX01000	Feb. 24, 2023	Feb.23, 2024
Signal Generator	Agilent	N5181A	MY50141953	Aug. 30, 2023	Aug. 29, 2024
EPM Series Power Meter	KEYSIGHT	N1914A	MY61180020	Jun. 20, 2023	Jun. 19, 2024
Power Sensor	KEYSIGHT	E9301A	MY61130007	Jun. 20, 2023	Jun. 19, 2024
Power Sensor	KEYSIGHT	E9301A	MY61130011	Jun. 20, 2023	Jun. 19, 2024
Radio Frequency Switch	Tonscend	JS0806s	21E8060428	N/A	N/A
Microwave Power amplifier	Micotop	MPA-80-1000- 250	MPA2105144	Jun. 20, 2023	Jun. 19, 2024
Microwave Power amplifier	Micotop	MPA-1000-600 0-100	MPA2105150	Jun. 20, 2023	Jun. 19, 2024
Electrical Fast	Fransient/ Surg	e/ Voltage Dip	and Interrupti	on Test	
Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Due Date
Simulator	EMTEST	UCS500N5	V0948105575	Jun. 20, 2023	Jun. 19, 2024
Auto-transformer	EMTEST	V4780S2	0109-41	Jun. 20, 2023	Jun. 19, 2024
Coupling Clamp	EMTEST	HFK	1109-04	Jun. 20, 2023	Jun. 19, 2024
Conducted Imm	nunity Test				•
Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Due Date
RF Generator	FRANKONIA	CIT-10/75	126B1126	Jun. 20, 2023	Jun. 19, 2024
Attenuator	FRANKONIA	59-6-33	A413	Jun. 20, 2023	Jun. 19, 2024
M-CDN	LUTHI	L-801 M2/M3	2599	Jun. 20, 2023	Jun. 19, 2024
AF2-CDN	LUTHI	L-801:AF2	2538	Feb. 23, 2023	Feb.22, 2024
EM Injection Clamp	LUTHI	EM101	35958	Jun. 20, 2023	Jun. 19, 2024



Page: 16 of 60

5 Conducted Disturbance Test (AC Port)

5.1 Test Standard and Limit

5.1.1 Test Standard

EN 55032:2015/A1:2020

5.1.2 Test Limit

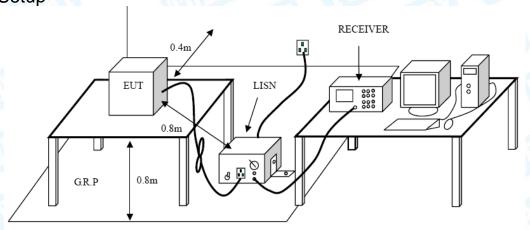
Table A.9 – Requirements for conducted emissions from the AC mains power ports of Class A equipment

Applicabl				
1. AC mai	ns power ports (3.1.1)			
Table clause	Frequency range MHz	Coupling device (see Table A.8)	Detector type / bandwidth	Class A limits dB(μV)
A9.1	0,15 to 0,5	ABABI	Oversi Barala / O lalla	79
	0,5 to 30	AMN	Quasi Peak / 9 kHz	73
A9.2	0,15 to 0,5	AMN	Average / O kl la	66
	0,5 to 30	AWIN	Average / 9 kHz	60

Table A.10 – Requirements for conducted emissions from the AC mains power ports of Class B equipment

AC maii	ns power ports (3.1.1)			
Table clause	Frequency range MHz	Coupling device (see Table A.8)	Detector type / bandwidth	Class B limits dB(μV)
A10.1	0,15 to 0,5			66 to 56
	0,5 to 5	AMN	Quasi Peak / 9 kHz	56
	5 to 30			60
A10.2	0,15 to 0,5			56 to 46
	0,5 to 5	AMN	Average / 9 kHz	46
	5 to 30			50

5.2 Test Setup







Page: 17 of 60

5.3 Test Procedure

The EUT was placed 0.8 meters from the horizontal ground plane with EUT being connected to the power mains through a line impedance stabilization network (LISN). All other support equipments powered from additional LISN(s). The LISN provide 50 Ohm/50uH of coupling impedance for the measuring instrument.

Interconnecting cables that hang closer than 40 cm to the ground plane shall be folded back and forth in the center forming a bundle 30 to 40 cm long.

I/O cables that are not connected to a peripheral shall be bundled in the center. The end of the cable may be terminated, if required, using the correct terminating impedance. The overall length shall not exceed 1 m.

LISN at least 80 cm from the nearest part of EUT chassis.

The bandwidth of EMI test receiver is set at 9kHz, and the test frequency band is from 0.15MHz to 30MHz.

5.4 Deviation From Test Standard No deviation

5.5 Test Data

Please refer to the Attachment A.





Page: 18 of 60

6 Conducted Emissions (Wired Network Port)

6.1 Test Standard and Limit

6.1.1 Test Standard

EN 55032:2015/A1:2020

6.1.2 Test Limit

Table A.11 – Requirements for asymmetric mode conducted emissions from Class A equipment

Applicable to

- 1. wired network ports (3.1.32)
- 2. optical fibre ports (3.1.25) with metallic shield or tension members
- 3. antenna ports (3.1.3)

Table clause	Frequency range MHz	Coupling device (see Table A.8)	Detector type / bandwidth	Class A voltage limits dB(μV)	Class A current limits dB(μA)
A11.1	0,15 to 0,5	A A N I	Overi Beek / O kHz	97 to 87	
	0,5 to 30	AAN	Quasi Peak / 9 kHz	87	/
	0,15 to 0,5	A A N I	Average / O kHz	84 to 74	n/a
	0,5 to 30	AAN	Average / 9 kHz	74	
A11.2	0,15 to 0,5	CVP	Ouasi Peak / 9 kHz	97 to 87	53 to 43
	0,5 to 30	and current probe		87	43
	0,15 to 0,5	CVP	CVP Average (0 kHz	84 to 74	40 to 30
	0,5 to 30	and current probe	Average / 9 kHz	74	30
A11.3	0,15 to 0,5		Overi Beels / O Islan		53 to 43
	0,5 to 30	Current Probe	Quasi Peak / 9 kHz		43
	0,15 to 0,5	Owner of Durch	A	- n/a	40 to 30
	0,5 to 30	Current Probe	Average / 9 kHz		30

The choice of coupling device and measurement procedure is defined in Annex C.

AC mains ports that also have the function of a wired network port shall meet the limits given in Table A.9.

The measurement shall cover the entire frequency range.

The application of the voltage and/or current limits is dependent on the measurement procedure used. Refer to Table C.1 for applicability.

Testing is required at only one EUT supply voltage and frequency.

Applicable to ports listed above and intended to connect to cables longer than 3 m.



19 of 60 Page:

Table A.12 – Requirements for asymmetric mode conducted emissions from Class B equipment

Applicable to

- 1. wired network ports (3.1.32)
- optical fibre ports (3.1.25) with metallic shield or tension members
 broadcast receiver tuner ports (3.1.8)
- 4. antenna ports (3.1.3)

Table clause	Frequency range MHz	Coupling device (see Table A.8)	Detector type / bandwidth	Class B voltage limits dB(μV)	Class B current limits dB(µA)
A12.1	0,15 to 0,5	A A N I	Oversi De ele / O lel le	84 to 74	
	0,5 to 30	AAN	Quasi Peak / 9 kHz	74	- /-
	0,15 to 0,5	A A N I	Average / O kHz	74 to 64	n/a
	0,5 to 30	AAN	Average / 9 kHz	64	
A12.2	0,15 to 0,5	CVP	Oversi Barata / O Idla	84 to 74	40 to 30
	0,5 to 30	and current probe	Quasi Peak / 9 kHz	74	30
	0,15 to 0,5	CVP	A	74 to 64	30 to 20
	0,5 to 30	and current probe	Average / 9 kHz	64	20
A12.3	0,15 to 0,5	Ourse at Dack	Oversi De ele / O lelle		40 to 30
	0,5 to 30	Current Probe	Quasi Peak / 9 kHz	/ -	30
	0,15 to 0,5	Ourse at Dack	A	n/a	30 to 20
	0,5 to 30	Current Probe	Average / 9 kHz		20

The choice of coupling device and measurement procedure is defined in Annex C.

Screened ports including TV broadcast receiver tuner ports are measured with a common-mode impedance of 150 $\Omega.$ This is typically accomplished with the screen terminated by 150 Ω to earth.

AC mains ports that also have the function of a wired network port shall meet the limits given in Table A.10.

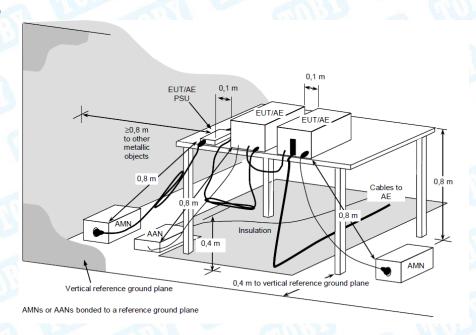
The measurement shall cover the entire frequency range.

The application of the voltage and/or current limits is dependent on the measurement procedure used. Refer to Table C.1 for applicability.

Measurement is required at only one EUT supply voltage and frequency.

Applicable to ports listed above and intended to connect to cables longer than 3 m.

6.2 Test Setup







Page: 20 of 60

6.3 Test Procedure

Detailed test procedure was following clause C.4.1 of EN 55032.

Frequency range 150kHz-30MHz was checked and EMI receiver measurement bandwidth was set to 9 kHz.

		D. C.	
Data Port	Measurement type	Coupling device	No. of Pairs
Balanced Unscreened	Voltage	AAN	≤ 4
Balanced Unscreened	Voltage and Current	CVP & Current probe	>4 or unable to AAN
Screened or Coaxial	Voltage	AAN	N/A
Screened or Coaxial	Voltage or Current	Current probe / "150Ω to 50Ω adaptor" / high impedance probe	N/A
Unbalanced cables	Voltage and Current	CVP & Current probe	N/A

6.4 Deviation From Test Standard
No deviation

6.5 Test Data

Not applicable.





Page: 21 of 60

7 Conducted Differential Voltage Emissions

7.1 Test Standard and Limit

7.1.1 Test Standard

EN 55032:2015/A1:2020

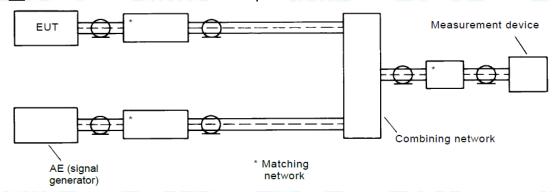
7.1.2 Test Limit

Requirements for Conducted differential voltage emissions from Class B equipment

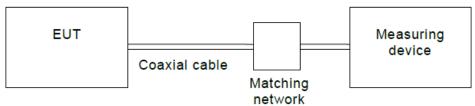
	F	Differential voltage limit @ 75Ω (dBuV)		
Applicability	Frequency range (MHz)	Other	Local Oscillator Fundamental	Local Oscillator Harmonics
Television receivers; Digital Video Recorders; PC TV broadcast receiver tuner cards;	30 ~ 950	46	46	46
Digital audio receivers;	950 ~ 2 150	46	54	54
Tuner units (not the LNB) for satellite signal reception	950 ~ 2 150	46	54	54
FM guidio receivers and DC tuper cords	30 ~ 300	46	54	50
FM audio receivers and PC tuner cards	300 ~ 1 000	46	54	52
FM any radios	30 ~ 300	46	66	59
FM car radios	300 ~ 1 000	46	66	52
RF modulator output ports connect to TV	30 ~ 950	46	76	46
broadcast receiver tuner ports	950 ~ 2150	46	7	54

7.2 Test Setup





RF modulator output port







Page: 22 of 60

7.3 Test Procedure

Detailed test procedure was following clause C4.2 and C4.3 of EN55032. Frequency range 30MHz – 2150MHz was checked and EMI receiver measurement bandwidth was set to 120kHz /1MHz.

7.4 Deviation From Test Standard No deviation

7.5 Test Data

This test is not applicable.





Page: 23 of 60

8 Radiated Emission Test

8.1 Test Standard and Limit

8.1.1 Test Standard

EN 55032:2015/A1:2020

8.1.2 Test Limit

Radiated Disturbance Test Limit

EDECLIENCY (MLI-)	Class A (at 3m)	Class B (at 3m)
FREQUENCY (MHz)	dBuV/m	dBuV/m
30 – 230	50	40
230 – 1000	57	47

Notes:

- (1) The limit for radiated test was performed according to as following: EN 55032
- (2) The tighter limit applies at the band edges.
- (3) Emission level (dBuV/m)=20log Emission level (uV/m).

Limits of Radiated Emission Measurement (Above 1000MHz)

FREQUENCY	Class A (dBuV/m) (at 3m)		Class B (dB	uV/m) (at 3m)
(MHz)	PEAK	AVERAGE	PEAK	AVERAGE
1000-3000	76	56	70	50
3000-6000	80	60	74	54

Notes:

(1) The lower limit applies at the transition frequency.

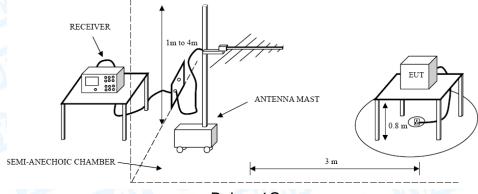
Frequency Range of Radiated Measurement

Highest frequency generated or Upper frequency of measurement used in the device or on which the device operates or tunes (MHz)	Range (MHz)
Below 108	1000
108 – 500	2000
500 – 1000	5000
Above 1000	5th harmonic of the highest frequency or 6 GHz, whichever is lower

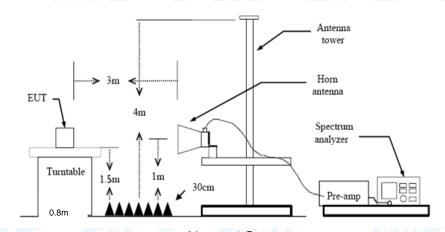


Page: 24 of 60

8.2 Test Setup



Below-1G



Above 1G

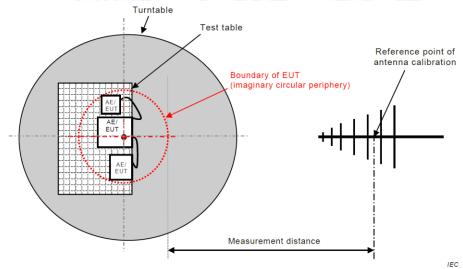


Figure C.1 - Measurement distance





Page: 25 of 60

8.3 Test Procedure

The EUT was placed on the top of a rotating table 0.8 meters above the ground at a 3m. The table was rotated 360 degrees to determine the position of the highest radiation.

The EUT and local AE shall be arranged in the most compact practical arrangement within the test volume, while respecting typical spacing and the requirements defined in Annex D. The central point of the arrangement shall be positioned at the centre of the turntable. The measurement distance is the shortest horizontal distance between an imaginary circular periphery just encompassing this arrangement and the calibration point of the antenna. See Figure C.1 and Figure C.2.

The height of the equipment or of the substitution antenna shall be 0.8 m; the height of the test antenna shall vary between 1 m to 4 m. Both horizontal and vertical polarizations of the antenna are set to make the measurement.

The initial step in collecting radiated emission data is a spectrum Quasi Peak detector mode scanning the measurement frequency range.

If the Peak Mode measured value compliance with and lower than Quasi Peak Mode Limit, the EUT shall be deemed to meet QP Limits and then no additional QP Mode measurement performed.

- 8.4 Deviation From Test Standard No deviation
- 8.5 Test Data
 Please refer to the Attachment B.





Page: 26 of 60

9 Harmonic Current Emission Test

9.1 Test Standard and Limit

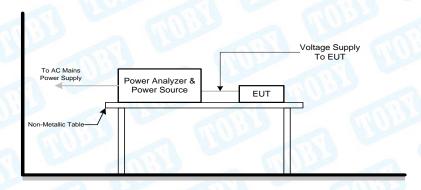
9.1.1 Test Standard

EN IEC 61000-3-2:2019/A1:2021

9.1.2 Test Limit

Limits for Class A equipment			Limits for Class D equipment			
Odd Harmonics		Even Harmonics		Harmonic Order	Maximum	Maximum
Harmonic Order (n)	Maximum permissible harmonic Current (A)	Harmonic Order (n)	Maximum permissible harmonic Current (A)	(n)	Permissible Harmonic Current per watt (mA/W)	Permissible Harmonic Current (A)
3	2.30	2	1.08	3	3.4	2.30
5	1.14	4	0.43	5	1.9	1.14
7	0.77	6	0.30	7	1.0	0.77
9	0.40	8≤n≤40	0.23X8/n	9	0.5	0.40
11	0.33	N W		11	0.35	0.33
13	0.21	18.0		15≤n≤39	3.85/n	0.15X15/n
15≤n≤39	0.15X15/n	11		(odd harmonics only)		1:15

9.2 Test Setup



9.3 Test Procedure

The EUT was placed on the top of a wooden table 0.8 meters above the ground and operated to produce the maximum harmonic components under normal operating conditions.

The classification of EUT is according to section 5 of EN 61000-3-2. The EUT is classified as follows:

- Class A: Balanced three-phase equipment, Household appliances excluding equipment as Class D, Tools excluding portable tools, Dimmers for incandescent lamps, audio equipment, equipment not specified in one of the three other classes.
- Class D: Equipment having a specified power less than or equal to600 W of the following types: Personal computers and personal computer monitors and television receivers.
- 9.4 Deviation From Test Standard No deviation
- 9.5 Test Data





Page: 27 of 60

10 Voltage Fluctuation and Flicker Test

10.1 Test Standard and Limit

10.1.1 Test Standard

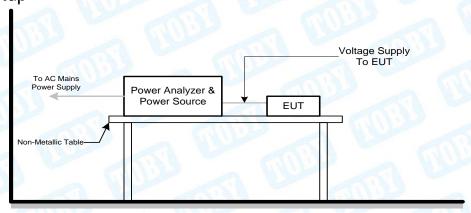
EN 61000-3-3:2013/A2:2021

10.1.2 Test Limit

Flicker Test Limit

Test Items	Limits
Pst	1.0
dc	3.3%
dmax	4.0%
dt	Not exceed 3.3% for 500ms

10.2 Test Setup



10.3 Test Procedure

Fluctuation and Flickers Test:

Tests was performed according to the Test Conditions/Assessment of Voltage Fluctuations specified in Clause 5.0/6.0 of IEC555-3 and/or Clause 6.0/4.0 of IEC/EN 61000-3-3 depend on which standard adopted for compliance measurement.

All types of harmonic current and/or voltage fluctuation in this report are assessed by direct measurement using flicker-meter.

For the actual test configuration, please refer to the related Item-Block Diagram of system tested.

10.4 Deviation From Test Standard

No deviation

10.5 Test Data

Please refer to the Attachment C.





Page: 28 of 60

11 Electrostatic Discharge Immunity Test

11.1 Test Standard and Limit

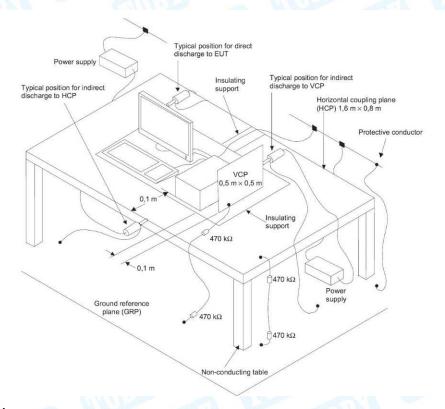
11.1.1 Test Standard

EN 55035:2017/A11:2020 EN 61000-4-2: 2009

11.1.2 Test Level

Discharge Impedance:	330 ohm/ 150pF	
Discharge Voltage:	Air Discharge: 2kV/4kV/8kV(Direct) Contact Discharge: 2kV/4kV (Direct /Indirect)	
Polarity:	Positive& Negative	
Discharge Mode:	Single Discharge	
Discharge Period:	1 second minimum	

11.2 Test Setup



11.3 Test Procedure

The test method shall be in accordance with CENELEC EN 61000-4-2 [2], clauses 6, 7 and 8.

For radio equipment and ancillary equipment the following requirements and evaluation of test results shall apply.

The test severity level for contact discharge shall be ±4 kV and for air discharge ±8 kV. All other details, including intermediate test levels, are contained within CENELEC EN 61000-4-2 [2], clause 5.

Electrostatic discharges shall be applied to all exposed surfaces of the EUT except where the user documentation specifically indicates a requirement for appropriate protective measures (as specified in CENELEC EN 61000-4-2 [2], clauses 8.3.2 and 8.3.3).





Page: 29 of 60

11.4 Deviation From Test Standard
No deviation

11.5 Test Data
Please refer to the Attachment D.





Page: 30 of 60

12 Radiated Electromagnetic Field Immunity test

12.1 Test Standard and Limit

12.1.1 Test Standard

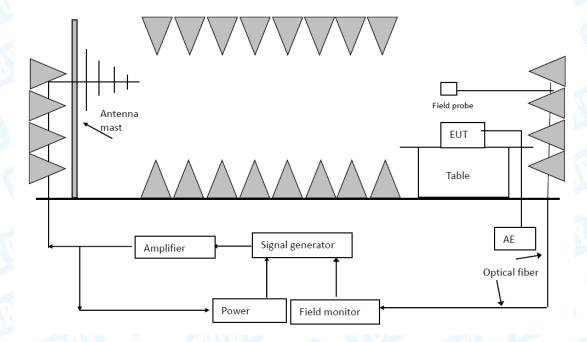
EN 55035:2017/A11:2020 EN IEC 61000-4-3:2020

12.1.2 Test Level

Test Level for Radiated Electromagnetic Field Immunity Test

Port	Test Specification
Enclosure Port	80-1000MHz, 1800MHz, 2600MHz, 3500MHz, 5000MHz
ULL TO THE TOTAL THE TOTAL TO T	3 V/m
	80 % AM (1kHz)

12.2 Test Setup







Page: 31 of 60

12.3 Test Procedure

The test method shall be in accordance with CENELEC EN 61000-4-3 [3], clauses 6, 7 and 8.

The following requirements and evaluation of test results shall apply:

• the test level shall be 3 V/m (measured unmodulated). The test signal shall be amplitude modulated to a depth of 80 % by a sinusoidal audio signal of 1 000 Hz.

If the wanted signal is modulated at 1 000 Hz, then an audio signal of 400 Hz shall be used:

- the test shall be performed over the frequency range 80 MHz to 6 000 MHz with the exception of the exclusion band for transmitters, receivers and duplex transceivers (see clause 4.3), as appropriate;
- for receivers and transmitters the stepped frequency increments shall be 1 % frequency increment of the momentary used frequency;
- the dwell time of the test phenomena at each frequency shall not be less than the time necessary for the EUT to be exercised and to be able to respond;

NOTE: Dwell time is product dependent.

the frequencies selected and used during the test shall be recorded.

All the scanning conditions are as following:

Condition of Test	Remark	
Fielded Strength	3V/m	
Radiated Signal	80%AM,1kHz Since Wave	
Scanning Frequency	80-1000MHz, 1800MHz, 2600MHz, 3500MHz, 5000MHz	

12.4 Deviation From Test Standard No deviation

12.5 Test Data

Please refer to the Attachment E.





Page: 32 of 60

13 Electrical Fast Transient/Burst Test

13.1 Test Standard and Limit

13.1.1 Test Standard

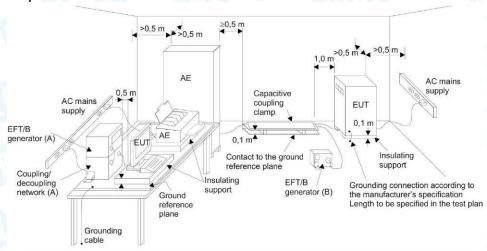
EN 55035:2017/A11:2020 EN 61000-4-4: 2012

13.1.2 Test Level

Test Level for Electrical Fast Transient Test

LODGE CONTRACTOR	On Switching Adapter Lines	On I/O (Input/Output) Signal data and control lines	
Test Voltage:	1 KV	0.5 KV	
Polarity:	Positive& Negative		
Impulse Wave Shape:	5/50ns		
Burst Duration: 15ms		15ms	
Burst Period:	300ms		
Test Duration:	Not less than 1 min		

13.2 Test Setup



13.3 Test Procedure

The test method shall be in accordance with CENELEC EN 61000-4-4 [4], clauses 7 and 8.

The following requirements and evaluation of test results shall apply:

- the test level for signal ports, wired network ports (excluding xDSL), and control ports shall be 0,5 kV open circuit voltage at a repetition rate of 5 kHz as given in CENELEC EN 61000-4-4 [4], clause 5;
- the test level for xDSL wired network ports shall be 0,5 kV open circuit voltage at a repetition rate of 100 kHz as given in CENELEC EN 61000-4-4 [4], clause 5;
- the test level for DC power input ports shall be 0,5 kV open circuit voltage at a repetition rate of 5 kHz as given CENELEC EN 61000-4-4 [4], clause 5;
- the test level for AC mains power input ports shall be 1 kV open circuit voltage at a repetition rate of 5 kHz as given CENELEC EN 61000-4-4 [4], clause 5.

13.4 Deviation From Test Standard No deviation

12.5 Test Data

Please refer to the Attachment F.





Page: 33 of 60

14 Surge Immunity Test

14.1 Test Standard and Limit

14.1.1 Test Standard

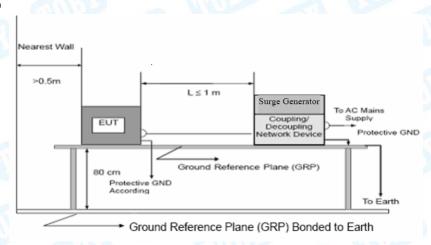
EN 55035:2017/A11:2020 EN 61000-4-5:2014/A1:2017

14.1.2 Test Level

Test Level for Surge Immunity Test

	Test Level for Surge Infiniality Test	
Basic Standard:	EN 61000-4-5	
	Analogue/digital data ports: 1KV (see a)	
Test Requirement:	DC network power ports: 0.5KV	
	AC mains power ports: 1KV(Line-Line), 2KV(Line-earth)	
T _r /T _h	1.2/50us, 10/700us	
Polarity:	Positive/Negative	
Phase Angle:	0/90/180/270	
Pulse Repetition Rate: 1 time/min.(maximum)		
Number of Tests:	5 positive and 5 negative at selected points	
a: Port type: coaxial or shie	lded. Apply: shield to ground.	

14.2 Test Setup



14.3 Test Procedure

- 1) Set the parameters of the CW generator and interference generator as shown in tables 4.2.9.2-1 and 4.2.9.2-2.
- 2) Set the power level of the UE according to tables 4.2.9.2-1 and 4.2.9.2-2 with a ±1 dB tolerance.
- 3) Measure the BER of DCH received from the UE at the SS.

Details of initial conditions for UEs supporting UTRA FDD can be found in ETSI TS 134 121-1 [1], clause 6.7.

14.4 Deviation From Test Standard

No deviation

14.5 Test Data

Please refer to the Attachment G.





Page: 34 of 60

15 RF Common Mode

15.1 Test Standard and Limit

15.1.1 Test Standard

EN 55035:2017/A11:2020 EN 61000-4-6: 2014

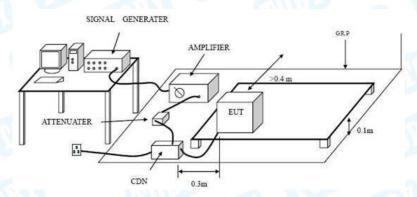
15.1.2 Test Level

Test Level for RF Common Mode

Port	Test Specification	
4000	0.15MHz~10MHz 3V(r.m.s.) (unmodulated)	
Input AC power port/ Signal Port/	10MHz~30MHz 3V to 1V(r.m.s.) (unmodulated)	
Input DC Port	30MHz~80MHz 1V(r.m.s.) (unmodulated)	
Test Signal	80% AM modulated sine wave, 1KHz	

Note: Only applies when the overall cable length between the EUT and another item of active equipment may be greater than 3 m.

15.2 Test Setup



15.3 Test Procedure

The following requirements and evaluation of test results shall apply:

- the test level shall be severity level 2 as given in CENELEC EN 61000-4-6 [6], clause 5 corresponding to 3 V rms unmodulated. The test signal shall then be amplitude modulated to a depth of 80 % by a sinusoidal audio signal of 1 000 Hz. If the wanted signal is modulated at 1 000 Hz, then the test signal of 400 Hz shall be used;
- the test shall be performed over the frequency range 150 kHz to 80 MHz with the exception of an exclusion band for transmitters, and for receivers and duplex transceivers, (see clause 4.3);
- for receivers and transmitters the stepped frequency increments shall be 1 % frequency increment of the momentary frequency in the frequency range 150 kHz to 80 MHz;
- the injection method to be used shall be selected according to the basic standard CENELEC EN 61000-4-6 [6], clause 7;
- responses on receivers or receiver parts of transceivers occurring at discrete frequencies which are narrow band responses (spurious responses), are disregarded from the test (as specified in clause 4); the dwell time of the test





Page: 35 of 60

phenomena at each frequency shall not be less than the time necessary for the EUT to be exercised and to be able to respond;

• the frequencies of the immunity test signal selected and used during the test shall be recorded.

15.4 Deviation From Test Standard
No deviation

15.5 Test Data

Please refer to the Attachment H.





Page: 36 of 60

16 Power frequency Magnetic Field Immunity Test

16.1 Test Standard and Limit

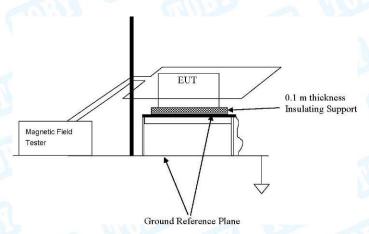
16.1.1 Test Standard

EN 55035:2017/A11:2020 EN 61000-4-8:2010

16.1.2 Test Level

Level	Field Strength A/m	
	1	
2	3	
3	10	
4	30	
5	100	
X	Special	

16.2 Test Setup



16.3 Test Procedure

The EUT is placed in the middle of a induction coil (1*1m), under which is a 1*1*0.1m (high) table, this small table is also placed on a larger table, 0.8 m above the ground. The X, Y and Z polarization of the induction coil is set on test, so that each side of the EUT is affected by the magnetic field. Also can reach the same aim by change the position of the FUT

16.4 Deviation From Test Standard No deviation

16.5 Test Data

Not applicable.





Page: 37 of 60

17 Voltage Dips and Interruptions Immunity Test

17.1 Test Standard and Limit

17.1.1 Test Standard

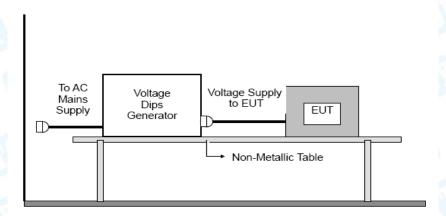
EN 55035:2017/A11:2020 EN IEC 61000-4-11:2020

17.1.2 Test Level

Test Level for Voltage Dips and Interruptions

Basic Standard:	EN IEC 61000-4-11
Required Performance:	B(For 100%, 0.5 cycle Voltage Dips) C(For 70%, 25 cycles for 50Hz, 30 cycles for 60Hz Voltage Dips) C(For 100%, 250 cycles for 50Hz, 300 cycles for 60Hz Voltage Interruptions)
Test Duration Time:	Minimum three test events in sequence
Interval Between Event:	Minimum ten seconds
Phase Angle:	0°/45°/90°/135°/180°/225°/270°/315°/360°
Test Cycle:	3 times

17.2 Test Setup



17.3 Test Procedure

The following requirements and evaluation of test results shall apply.

The test method shall be in accordance with CENELEC EN 61000-4-11

The test levels shall be:

For 100%, 0.5 cycle Voltage Dips)

For 70%, 25 cycles for 50Hz, 30 cycles for 60Hz Voltage Dips)

For 100%, 250 cycles for 50Hz, 300 cycles for 60Hz Voltage Interruptions)

17.4 Deviation From Test Standard

No deviation

17.5 Test Data

Please refer to the Attachment I.





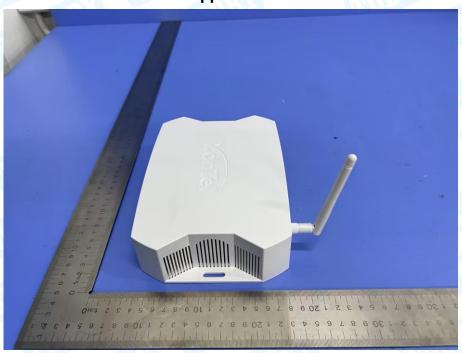
Page: 38 of 60

18 Photographs - Constructional Details

Photo 1 Appearance of EUT



Photo 2 Appearance of EUT







Page: 39 of 60

Photo 3 Appearance of EUT

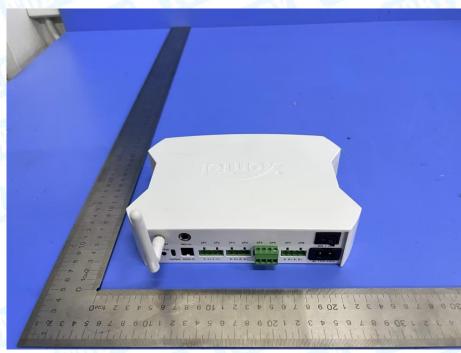
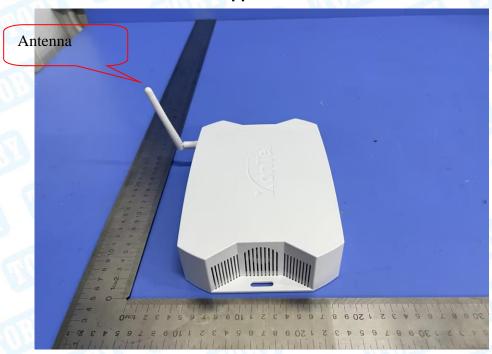


Photo 4 Appearance of EUT







Page: 40 of 60

Photo 5 Appearance of EUT



Photo 6 Internal of EUT







Page: 41 of 60

Photo 7 Internal of PCB

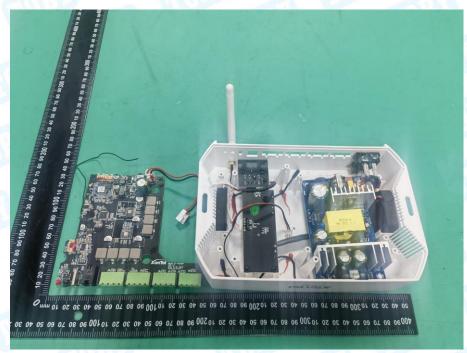
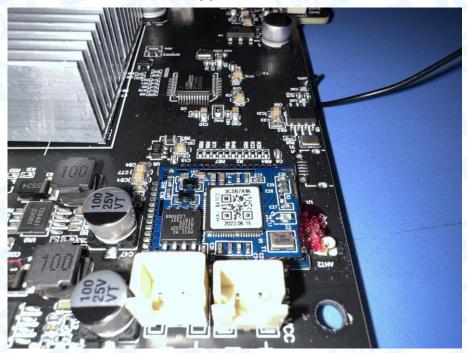


Photo 8 Appearance of PCB







Report No.: TBR-C-202308-0123-8 Page: 42 of 60

Photo 9 Appearance of PCB

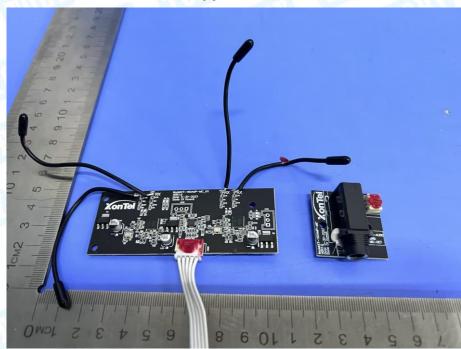
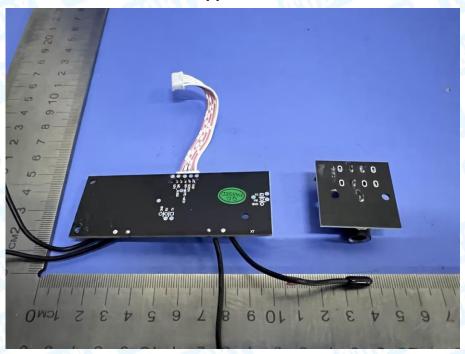


Photo 10 Appearance of PCB







Page: 43 of 60

19 Photographs - Test Setup

Conducted Emission Test Setup



Radiated Emission Test Setup-Below 1G

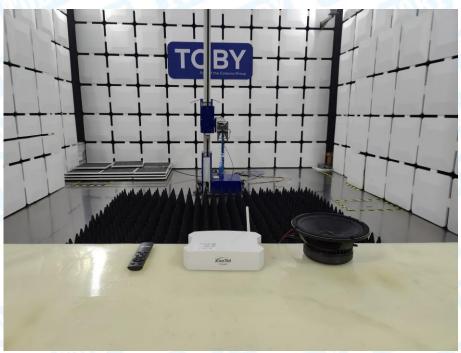






Page: 44 of 60

Radiated Emission Test Setup-Above 1G



Voltage fluctuations & flicker Test Setup







Report No.: TBR-C-202308-0123-8 Page: 45 of 60

Electrostatic Discharge Test Setup



EFT, Surge, Voltage Dips Test Setup

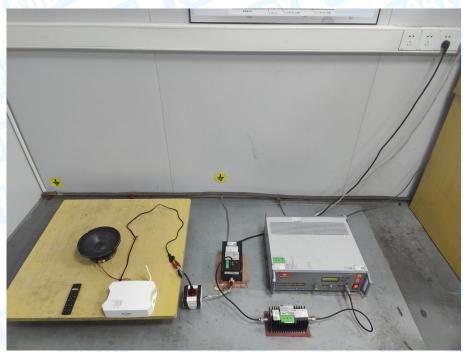






Report No.: TBR-C-202308-0123-8 Page: 46 of 60

Radio-frequency, Continuous Conducted Disturbance Test Setup



Radiated Immunity Test Setup

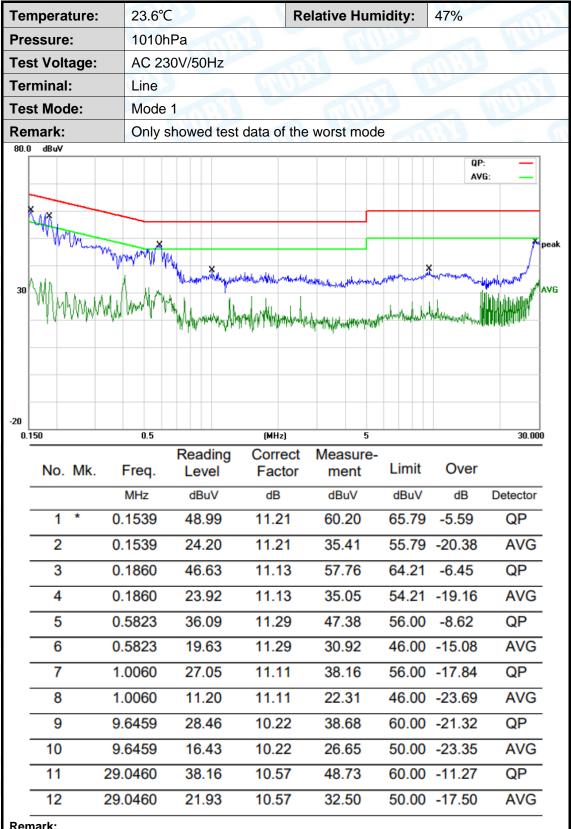






47 of 60 Page:

Attachment A--Conducted Emission Data (AC Mains)



- 1. Corr. Factor (dB) = LISN Factor (dB) + Cable Loss (dB)
- 2. Margin (dB) =Quas<u>iPeak/Average (dBuV)-Limit (dBuV)</u>





Page: 48 of 60

	perature:	23.6°C		Re	lative Hum	idity:	47%	
Pres	sure:	1010h	Pa	" CA	1 the		A STATE	
Test	Voltage:	AC 23	0V/50Hz					AHO:
Term	ninal:	Neutra	I White					
Test	Mode:	Mode	1	CAIR:		3 M		
Rem	nark:	Only s	howed test	data of the	worst mode	9		MAIN
30	AMMANA AM	1/4/1/1/1/1/1/1/1/1/1/1/1/1/1/1/1/1/1/1	And the second of the second o	** <mark> </mark>	haranday many	monde porter	QP:	
-20 0.15		0.5	Reading	(MHz) Correct	5 Measure-			30.000
	No. Mk.		Reading Level			Limit	Over	
		Freq.	Level	Correct Factor	Measure- ment dBuV	dBuV	dB	Detector
		. Freq.	Level	Correct Factor	Measure- ment			
	No. Mk.	Freq.	Level	Correct Factor	Measure- ment dBuV	dBuV 66.00	dB	Detector
	No. Mk.	MHz 0.1499	dBuV 50.25	Correct Factor dB 11.20	Measure- ment dBuV 61.45	dBuV 66.00	dB -4.55	Detector QP
	No. Mk.	MHz 0.1499 0.1499	dBuV 50.25 23.75	Correct Factor dB 11.20 11.20	Measure- ment dBuV 61.45 34.95	dBuV 66.00 56.00 60.02	dB -4.55 -21.05	Detector QP AVG
	No. Mk.	MHz 0.1499 0.1499 0.3082	dBuV 50.25 23.75 39.76	Correct Factor dB 11.20 11.20 11.33	Measure- ment dBuV 61.45 34.95 51.09	dBuV 66.00 56.00 60.02	dB -4.55 -21.05 -8.93 -20.28	Detector QP AVG QP
	No. Mk.	MHz 0.1499 0.1499 0.3082 0.3082	Level dBuV 50.25 23.75 39.76 18.41	Correct Factor dB 11.20 11.20 11.33	Measure- ment dBuV 61.45 34.95 51.09 29.74	dBuV 66.00 56.00 60.02 50.02 56.00	dB -4.55 -21.05 -8.93 -20.28	Detector QP AVG QP AVG
	No. Mk. 1 * 2 3 4 5	MHz 0.1499 0.1499 0.3082 0.3082 0.5819	Level dBuV 50.25 23.75 39.76 18.41 39.91	Correct Factor dB 11.20 11.20 11.33 11.33	Measure- ment dBuV 61.45 34.95 51.09 29.74 50.98	dBuV 66.00 56.00 60.02 50.02 56.00 46.00	dB -4.55 -21.05 -8.93 -20.28 -5.02	Detector QP AVG QP AVG QP
	No. Mk. 1 * 2 3 4 5 6	MHz 0.1499 0.1499 0.3082 0.3082 0.5819	Level dBuV 50.25 23.75 39.76 18.41 39.91 23.76	Correct Factor dB 11.20 11.20 11.33 11.33 11.07 11.07	Measure- ment dBuV 61.45 34.95 51.09 29.74 50.98 34.83	dBuV 66.00 56.00 60.02 50.02 56.00 46.00	dB -4.55 -21.05 -8.93 -20.28 -5.02 -11.17	Detector QP AVG QP AVG QP AVG
	No. Mk. 1 * 2 3 4 5 6 7	MHz 0.1499 0.1499 0.3082 0.3082 0.5819 0.5819 0.9419	Level dBuV 50.25 23.75 39.76 18.41 39.91 23.76 30.28	Correct Factor dB 11.20 11.20 11.33 11.07 11.07	Measure- ment dBuV 61.45 34.95 51.09 29.74 50.98 34.83 41.29	dBuV 66.00 56.00 60.02 50.02 56.00 46.00 46.00	dB -4.55 -21.05 -8.93 -20.28 -5.02 -11.17 -14.71	Detector QP AVG QP AVG QP AVG QP
	No. Mk. 1 * 2 3 4 5 6 7	MHz 0.1499 0.1499 0.3082 0.3082 0.5819 0.5819 0.9419	Level dBuV 50.25 23.75 39.76 18.41 39.91 23.76 30.28 15.34	Correct Factor dB 11.20 11.20 11.33 11.33 11.07 11.07 11.01	Measure- ment dBuV 61.45 34.95 51.09 29.74 50.98 34.83 41.29 26.35	dBuV 66.00 56.00 60.02 56.00 46.00 56.00 56.00	dB -4.55 -21.05 -8.93 -20.28 -5.02 -11.17 -14.71 -19.65	Detector QP AVG QP AVG QP AVG AVG
	No. Mk. 1 * 2 3 4 5 6 7 8 9	MHz 0.1499 0.1499 0.3082 0.3082 0.5819 0.5819 0.9419 0.9419 1.8899	Level dBuV 50.25 23.75 39.76 18.41 39.91 23.76 30.28 15.34 30.81	Correct Factor dB 11.20 11.33 11.33 11.07 11.07 11.01 10.56	Measure- ment dBuV 61.45 34.95 51.09 29.74 50.98 34.83 41.29 26.35 41.37	dBuV 66.00 56.00 60.02 56.00 46.00 56.00 56.00	dB -4.55 -21.05 -8.93 -20.28 -5.02 -11.17 -14.71 -19.65 -14.63 -15.18	Detector QP AVG QP AVG QP AVG QP AVG QP AVG

- Remark:
 1. Corr. Factor (dB) = LISN Factor (dB) + Cable Loss (dB)
- 2. Margin (dB) =QuasiPeak/Average (dBuV)-Limit (dBuV)





Page: 49 of 60

Attachment B--Radiated Emission Test Data

----Below 1GHz



- 1. Corr. = Antenna Factor (dB/m) + Cable Loss (dB)
- 2. QuasiPeak (dBμV/m)= Corr. (dB/m)+ Read Level (dBμV)
- 3. Margin (dB) = QuasiPeak (dBµV/m)-Limit QPK(dBµV/m)





Page: 50 of 60

		4.02	CALL			10 15
Temperature:	24.6℃	R	elative Humidity	: 52%	MAN DE	
Pressure:	1010hPa			183		
Test Voltage:	AC 230V/50Hz	20			2 1	MAG
Ant. Pol.	Vertical					
Test Mode:	Mode 1			Alter		
Remark:	Only showed tes	st data of the	e worst mode		EN.	M. C.
30 X X	3 4	5	6 MMM	032 ClassB-3M	Hadiation Margin -6	
-20						
No. Mk. Fre	Reading eq. Level	Correct Factor	Measure-		Over	1000.000
MH	lz dBuV	dB/m	dBuV/m dB	uV/m	dB	Detector
1 * 30.00	000 41.93	-8.20	33.73 40	0.00 -	-6.27	peak
2 43.50	056 48.13	-16.57	31.56 40	0.00 -	8.44	peak
3 64.88	863 48.73	-16.47	32.26 40	0.00 -	7.74	peak
4 111.3	468 48.64	-15.26	33.38 40	0.00 -	-6.62	peak
5 181.9	199 44.11	-13.31	30.80 40	0.00 -	-9.20	peak
6 252.9	482 41.12	-10.64	30.48 47	7.00 -	16.52	peak

- Remark:
 1. Corr. = Antenna Factor (dB/m) + Cable Loss (dB)
 2. QuasiPeak (dBμV/m)= Corr. (dB/m)+ Read Level (dBμV)
- 3. Margin (dB) = QuasiPeak (dB μ V/m)-Limit QPK(dB μ V/m)





Page: 51 of 60

----Above 1G

Temper	ature:	26°C				R	elativ	e Hur	nidity:	54	1%		A
Pressur	e:	101	0hPa			B				-			No
Test Vo	Itage:	AC	230V	//50Hz									
Ant. Pol	l.	Hori	izonta	al	571	M,	33		_ 5	1/1	11/100		1
Test Mo	de:	Mod	de 1						10		6		P
Remark	:	N/A	6	MA			1	MAR		K			
90.0 dBu	V/m												7
80													
70								E	N 55032 Cla	ssB Ra	adiation PE	AK	-
60								E	N 55032 Cla	ssB Ra	adiation AV	G	
50						+		,		+			
40	فيعتد بيار	V	homerana.	Charles and the state of the	- market market free	er the fee	Na Paris Name	1 	Carried Control of the Control of th	Martin	man Harris	(hyadroneeringen	peak
30	and the second	ALTO VALUE OF THE PARTY OF	order stone	tradescent layared	par plant	w Voney	www	mank mar	Called Caperon It and the cha	Madelle	المواطعة بالبعثر بالعراب الم	No of the party of the second	ly AVG
20	Mangaret Comment	-Martin Habburgan											
10													
0													+
1000.000	1500.00	2000.00	2500	0.00 30)00.00 (M	Hz)	400	0.00	4500.00	5000.0	00 550	0.00 6	
	Freque	ncv	Res	ading	Facto	ır	اما	vel	Limit		Margi	n	
No.	(MH			BuV)	(dB/m			V/m)		_	(dB)		ector
1	4220.0	000	53	3.99	-11.96	6	42	.03	74.00)	-31.9	7 pe	ak
										-			

- Remark: 1. Corr. = Antenna Factor (dB/m) + Cable Loss (dB) 2. Peak/AVG (dBμV/m)= Corr. (dB/m)+ Read Level (dBμV)
- 3. Margin (dB) = Peak/AVG (dB μ V/m)-Limit PK/AVG(dB μ V/m)





Page: 52 of 60

Tempe	rature:	26℃		F	Relative Hun	nidity:	54%	
Pressu	re:	101	0hPa		111111		1	
Test Vo	oltage:	AC :	230V/50Hz	18:11	CIII)	1192		CHIE.
Ant. Po	ol.	Vert	ical		av			
Γest M	ode:	Mod	le 1			0 1	No.	
Remarl	k:	N/A				13		
90.0 dB	uV/m							
80								
					E	N 55032 Clas	sB Radiation PEAK	
'0 <u> </u>								
SO					E	N 55032 Clas	sB Radiation AVG	
io								
10				1		and the second s	and the second section of the second	pea
HAMPARA	an manager of the second second	gopher warran	war white was proposed by	1 April 2	they are the other desired	orania anno Maria	May reference and work work of the	WHIPMAN AV
30	and and and advantaged	Marian Marketing	- hidyadiyakaraya	and the state of t	discourte de la			
20								
10								
,								
10								
1000.00	0 1500.00	2000.00	2500.00 30	000.00 (MHz)	4000.00	1500.00 5	5000.00 5500.0	00 6000.0
No.	Freque (MH	•	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/ı	3	Detector
1	3205.	000	52.40	-13.68	38.72	74.00	-35.28	peak
2 *	3215.	000	43.66	-13.68	29.98	54.00	-24.02	AVG

- 1. Corr. = Antenna Factor (dB/m) + Cable Loss (dB)
 2. Peak/AVG (dBμV/m)= Corr. (dB/m)+ Read Level (dBμV)
- 3. Margin (dB) = Peak/AVG (dB μ V/m)-Limit PK/AVG(dB μ V/m)





Page: 53 of 60

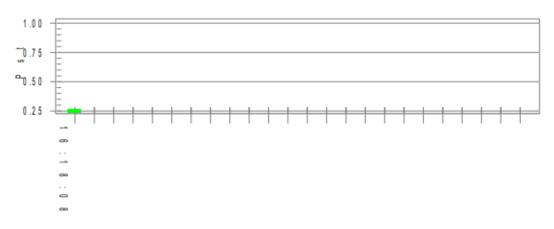
Attachment C--Voltage Fluctuation and Flicker Test Data

Temperature:	23.5℃	Relative Humidity:	54%
Pressure:	1008hPa		
Test Voltage:	AC 230V/50Hz	DE TRUE	
Test Mode:	Mode 1		DE TOUR
Remark:	Only showed test data	of the worst mode	
	Flicker Test Summa	arv per EN/IEC61000-3-3 (Run	time)

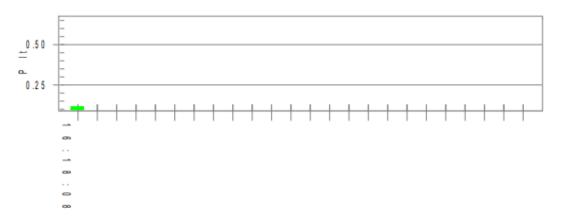
Test Result: Pass Status: Test Completed

Pst_i and limit line

European Limits



Plt and limit line



Parameter values recorded during the test:

Vrms at the end of test (Volt):

Highest dt (%):

T-max (mS): Highest dc (%): 0.00 Highest de (%): Highest Pst (10 min. period): Highest Plt (2 hr. period): 0.00 0.264 0.115

Test limit (%): Test limit (mS): Test limit (%): 500.0 **Pass** 3.30 **Pass** Test limit (%): 4.00 **Pass** Test limit: 1.000 Pass Test limit: 0.650 **Pass**





Page: 54 of 60

Attachment D--Electrostatic Discharge Test Data

Temperature:	23	.5℃		3)		9	1		Н	umi	dity	8	5	54%	ó		
Pressure(hpa):	10	80				11	15				1			9			J. Film	
Power supply:	AC	23	30/5	0Hz				1	77	T	est l	Mod	le:	1	Mod	de 1	1	I WILL
THE STATE OF THE S	9		A Maria	7	est	Le	vel	(kV) aı	nd l	Res	ult	N	1			early)	
Location			4ir I	Dis	cha	rge			6	Cor	ntac	t D	isc	har	ge	A	Criteria	Result
Location	- 2	2	4	4	8	3	1	5	2	2	4	1	6	3	8	3	Criteria	Nesult
33	+	1	+	-	+	_^	+		+	-	+	1	+	-	+			
A1	Α	Α	Α	Α	Α	Α	/	1	/	1	1	1	1	1	/	1	В	PASS
A2	Α	Α	Α	Α	Α	Α	1	1	/	1	/	1	1	1	1	/	В	PASS
A3	Α	Α	Α	Α	Α	Α	1	1	/	1	1	/	1	/	1	1	В	PASS
A4	Α	Α	Α	Α	Α	Α	/	/	1	1	1	/	/	/	1	1	В	PASS
A5	Α	Α	Α	Α	Α	Α	/	/	/	/	1	/	/	1	/	/	В	PASS
A6	Α	Α	Α	Α	Α	Α	1	/	1	1	/	/	/	1	1	1	В	PASS
A7	Α	Α	Α	Α	Α	Α	/	1	/	1	/	1	/	/	1	1	В	PASS
A8	Α	Α	Α	Α	Α	Α	/	1	1	/	1	/	1	/	/	/	В	PASS
A9	Α	Α	Α	Α	Α	Α	1	1	1	/	1	1	1	1	1	1	В	PASS
							6		18				1	11/4				6300
Color Color				_		t Le	eve	l(k\	/) a	nd	Res		•			-		
				HC	P					1		VC	Р	5			6	
Location	2	2	4	4	(3	8	3	2	2	-	1	6	3	8	3	Criteria	Result
	+		+		+	-	+	-	+	1	+) -	+	-	+	1		
Front	/	/	Α	Α	1	/	1	/	/	/	Α	Α	1	/	/	1	В	PASS
Back	/	/	Α	Α	/	/	1	/	/	/	Α	Α	1	1	/	1	В	PASS
Left	1	/	Α	Α	/	1	1	1	1	/	Α	Α	/	/	1	1	В	PASS
Right	/	/	Α	Α	/	1	/	1	/	1	Α	Α	1	/	1	1	В	PASS

Note: "/" Representative the test not applicable

Criteria A: There was no change operated with initial operating during the test.

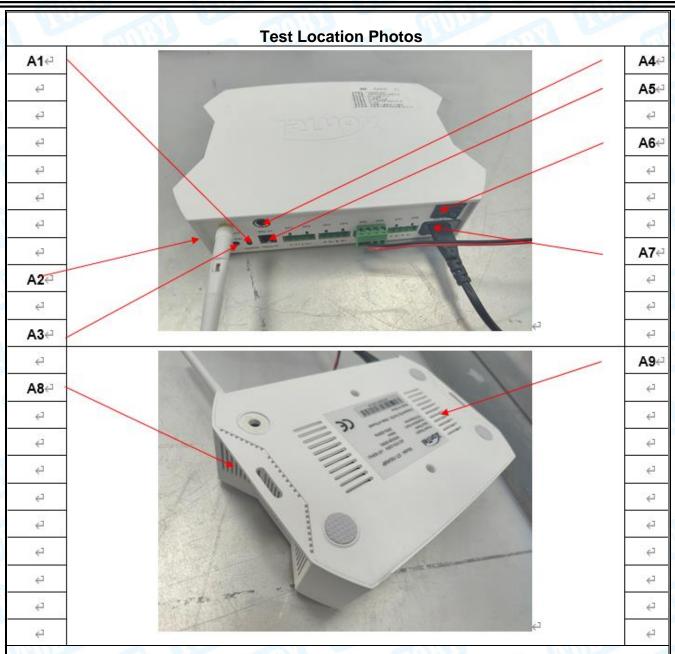
Criteria B: The EUT function loss during the test, but self-recoverable after the test.

Criteria C: The system shut down during the test.





Page: 55 of 60



Note:

- 1) Criteria A: There was no change operated with initial operating during the test.
- 2) Criteria B: The EUT function loss during the test, but self-recoverable after the test.
- 3) Criteria C: The system shut down during the test.





Page: 56 of 60

Attachment E--RF Field Strength Susceptibility Test Data

Temperature : 23.8℃ Humidity : 50%

Pressure(hpa): 1008

Power supply : AC 230V/50Hz Test Mode : Mode 1

Required Performance Criteria: A

Modulation: AM 80%, Field strength: 3V/m, Pulse: 1 kHz.

	A	ctual Perforn	nance Criteria	a	
Antenna	Fre	quency Rang	e : 80~1000M	Hz	Result
Polarity		EUT Po	osition		
	Front	Right	Rear	Left	
н	Α	A	A	A	PASS
V	A	Α	A	Α	PASS

				Freq	uency				
	1800	MHz	2600	MHz	3500	MHz	5000	MHz	
EUT Position		U	A	ntenna	Polari	ty	400		Result
THE WAY	Н	V	Н	٧	Н	V	Н	V	
Front	A	Α	A	Α	Α	Α	Α	A	PASS
Right	A	Α	Α	Α	A	A	Α	A	PASS
Rear	Α	Α	Α	Α	Α	Α	Α	Α	PASS
Left	Α	Α	Α	Α	Α	Α	Α	Α	PASS

- 1) Criteria A: There was no change operated with initial operating during the test.
- 2) Criteria B: The EUT function loss during the test, but self-recoverable after the test.
- 3) Criteria C: The system shut down during the test.





Page: 57 of 60

Attachment F--Electrical Fast Transient/Burst Test Data

Temperature : 23.5°C Humidity : 54%

Pressure(hpa): 1008

Power supply : AC 230V/50Hz Test Mode : Mode 1

Required Performance Criteria: B

Line	Voltage		Performance teria	Actual Per Crite		Result
	(kV)	(+)	(-)	(+)	(-)	Nosan
L	1.0	В	В	Α	Α	PASS
N	1.0	В	В	A	Α	PASS
L-N	1.0	В	В	A	Α	PASS
PE	1.0	В	В	1		1
L-PE	1.0	В	В	N/	1 1	1
N-PE	1.0	В	В	I		
L-N-PE	1.0	В	В	1	1	1
RJ45 Port	0.5	В	В	1	1	1

- 1) Criteria A: There was no change operated with initial operating during the test.
- 2) Criteria B: The EUT function loss during the test, but self-recoverable after the test.
- 3) Criteria C: The system shut down during the test.





Page: 58 of 60

Attachment G--Surge Immunity Test Data

Temperature : 23.5°C Humidity : 54%

Pressure(hpa): 1008

Power supply : AC 230V/50Hz Test Mode : Mode 1

Required Performance Criteria: B

T_r/T_h: 1.2/50us for AC Power Port, T_r/T_h: 10/700us for data ports

Injected Line	Voltage (kV)	Pulse number	Phase	Act Perfori Crite	mance	Result	
	(KV)	Humber	40R7	(+)	(-)	(+)	(-)
		10	0°	Α	Α	PASS	PASS
The state of the s	1.0	10	90°	A	A	PASS	PASS
L-N	1.0	10	180°	Α	A	PASS	PASS
		10	270°	Α	Α	PASS	PASS
a W		100	0°	1	1	1	1
, pe 3	0.0		90°	1	I	1	1
L-PE	2.0	1	180°	1	1	100	1
	133	1/10	270°	1	1	1	1
TO U		1	0°	1	1	1	1
N. DE	0.0		90°		1		1
N-PE	2.0	1	180°	1	1	1	W.
	WHI TO	1	270°	1	1		1
RJ45 Port	1.0	10	+/-	1	1	1	1

- 1) Criteria A: There was no change operated with initial operating during the test.
- 2) Criteria B: The EUT function loss during the test, but self-recoverable after the test.
- 3) Criteria C: The system shut down during the test.





Page: 59 of 60

Attachment H--Conducted Immunity Test Data

Temperature : 23.5 °C Humidity : 54%

Pressure(hpa): 1008

Power supply : AC 230V/50Hz Test Mode : Mode 1

Required Performance Criteria: A

Frequency Range (MHz)	Injected Position	Voltage Level (e.m.f.)	Required Performance Criteria	Actual Performance Criteria	Result
0.15 ~ 10		3V(rms), AM 80% Modulated with 1 kHz	A	A	PASS
10 ~ 30	AC Mains	3V to 1V(rms), AM 80% Modulated with 1 kHz	A	A	PASS
30 ~ 80	DORR	1V(rms), AM 80% Modulated with 1 kHz	A	А	PASS
0.15 ~ 10	2027	3V(rms), AM 80% Modulated with 1 kHz		W/B1	1
10 ~ 30	RJ45 Port	3V to 1V(rms), AM 80% Modulated with 1 kHz	(A) (A)		1
30 ~ 80	y Con	1V(rms), AM 80% Modulated with 1 kHz	MORY	/ 1	,

- 1) Criteria A: There was no change operated with initial operating during the test.
- 2) Criteria B: The EUT function loss during the test, but self-recoverable after the test.
- 3) Criteria C: The system shut down during the test.





Page: 60 of 60

Attachment I--Voltage Dips and Interruptions Test Data

Temperature : 23.5 °C Humidity : 54%

Pressure(hpa): 1008

Power supply : AC 230V/50Hz Test Mode : Mode 1

Criterion: B&C

Test Level % UT	Voltage Dips & Short Interruptions % UT	Duration (in period)	Phase Angle	Required Performance Criteria	Result
0	100	250P	0°	C	Pass
70	30	25P	0°	C	Pass
0	100	0.5P	0°	В	Pass

Remark: U_T is the rated voltage for the equipment.

- 1) Criteria A: There was no change operated with initial operating during the test.
- 2) Criteria B: The EUT function loss during the test, but self-recoverable after the test.
- 3) Criteria C: The system shut down during the test.

----END OF REPORT----

